TOSHIBA Field Effect Transistor Silicon P Channel MOS Type (U-MOSIII)

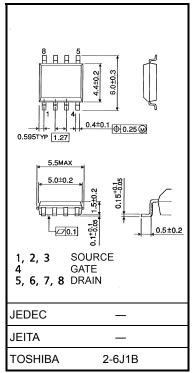
# **TPC8107**

Lithium Ion Battery Applications Notebook PC Applications Portable Equipment Applications

- Small footprint due to small and thin package
- Low drain-source ON resistance:  $R_{DS}$  (ON) = 5.5 m $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 31 \text{ S} (typ.)$
- Low leakage current:  $I_{DSS} = -10 \ \mu A \ (max) \ (V_{DS} = -30 \ V)$
- Enhancement mode:  $V_{th} = -0.8$  to -2.0 V ( $V_{DS} = -10$  V,  $I_D = -1$  mA)

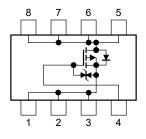
Character	ristics	Symbol	Rating	Unit
Drain-source voltage		V <sub>DSS</sub>	-30	V
Drain-gate voltage (R	<sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	-30	V
Gate-source voltage		V <sub>GSS</sub>	±20	V
Drain current	DC (Note 1)	ID	-13	А
Dialit current	Pulse (Note 1)	I <sub>DP</sub>	-52	
Drain power dissipati	on (t = 10 s) (Note 2a)	PD	1.9	W
Drain power dissipati	on (t = 10 s) (Note 2b)	PD	1.0	W
Single pulse avalanch	ne energy (Note 3)	E <sub>AS</sub>	219	mJ
Avalanche current		I <sub>AR</sub>	-13	А
Repetitive avalanche	energy Note 2a) (Note 4)	E <sub>AR</sub>	0.19	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature	range	T <sub>stg</sub>	-55 to 150	°C

#### Absolute Maximum Ratings (Ta = 25°C)



Weight: 0.080 g (typ.)

#### **Circuit Configuration**



Note: (Note 1), (Note 2), (Note 3) and (Note 4): See the next page.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

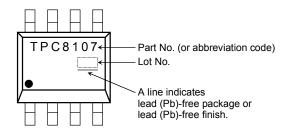
This transistor is an electrostatic-sensitive device. Please handle with caution.

Unit: mm

#### **Thermal Characteristics**

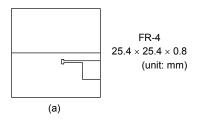
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient $(t = 10 \text{ s})$ (Note 2a)	R <sub>th (ch-a)</sub>	65.8	°C/W
Thermal resistance, channel to ambient $(t=10 \ s) \mbox{ (Note 2b)} \label{eq:kappa}$	R <sub>th (ch-a)</sub>	125	°C/W

#### Marking (Note 5)

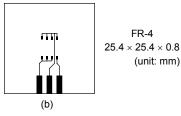


Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: (a) Device mounted on a glass-epoxy board (a)



(b) Device mounted on a glass-epoxy board (b)



Note 3:  $V_{DD} = -24 \text{ V}, \text{ T}_{ch} = 25^{\circ}\text{C}$  (initial), L = 1.0 mH, R<sub>G</sub> = 25  $\Omega$ , I<sub>AR</sub> = -13 A

Note 4: Repetitive rating: pulse width limited by maximum channel temperature

Note 5: • on lower left of the marking indicates Pin 1.

※ Weekly code: (Three digits)



Week of manufacture (01 for the first week of a year: sequential number up to 52 or 53) Year of manufacture

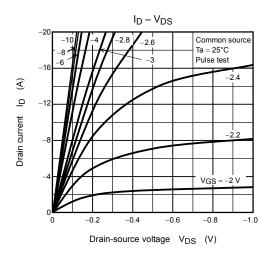
(The last digit of a year)

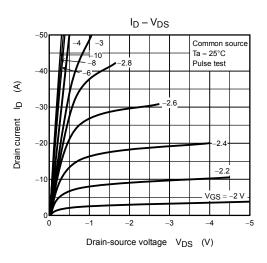
### Electrical Characteristics (Ta = 25°C)

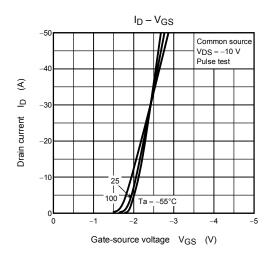
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cur	rent	I <sub>GSS</sub>	$V_{GS}=\pm 16~V,~V_{DS}=0~V$	_		±10	μA
Drain cut-OFF cu	irrent	I <sub>DSS</sub>	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	10		μA
Drain agurag bra		V (BR) DSS	$I_D = -10 \text{ mA}, V_{GS} = 0 \text{ V}$	-30			v
Drain-source bre	akuown vollage	V (BR) DSX	$I_D = -10$ mA, $V_{GS} = 20$ V	— — — — 10	v		
Gate threshold ve	eshold voltage V <sub>th</sub> V <sub>DS</sub> =		$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -1 \text{ mA}$	-0.8		-2.0	V
Drain-source ON resistance Forward transfer admittance		Decision	$V_{GS} = -4 \text{ V}, \text{ I}_{D} = -6.5 \text{ A}$	_	10	15	mΩ
		R <sub>DS</sub> (ON)	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -6.5 \text{ A}$	_	5.5	7.0	
Forward transfer admittance		Y <sub>fs</sub>	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -6.5 \text{ A}$	15.5	31	_	S
Input capacitance	è	C <sub>iss</sub>		_	5880	_	
Reverse transfer capacitance		C <sub>rss</sub>	$V_{DS}$ = -10 V, $V_{GS}$ = 0 V, f = 1 MHz	_	1000	_	pF
Output capacitance		C <sub>oss</sub>		_	1050	_	
Output capacitanc	Rise time	tr	$V_{GS} \stackrel{0}{} V \stackrel{1}{} I_{D} = -6.5 \text{ A}$	_	11	_	- ns
	Turn-ON time	t <sub>on</sub>		_	22	_	
	Fall time	t <sub>f</sub>		_	110		
	Turn-OFF time	t <sub>off</sub>	$V_{DD}\simeq -15~V \label{eq:VDD}$ Duty $\leq 1\%,~t_W=10~\mu s$	_	395		
Total gate charge (gate-source plus gate-drain)		Qg	$V_{DD} \simeq -24$ V, $V_{GS} = -10$ V, $I_D = -13$ A	_	130	_	nC
Gate-source charge 1		Q <sub>gs1</sub>		_	10		
Gate-drain ("miller") charge		Q <sub>gd</sub>		_	30	_	

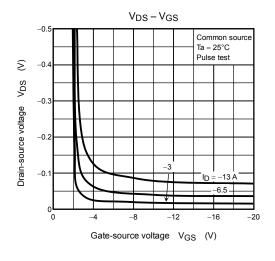
#### Source-Drain Ratings and Characteristics ( $Ta = 25^{\circ}C$ )

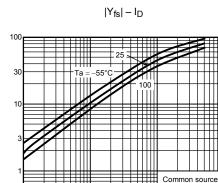
Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit	
Drain reverse current	Pulse	(Note 1)	IDRP	—	_		-52	А
Forward voltage (diode)			V <sub>DSF</sub>	$I_{DR} = -13 \text{ A}, V_{GS} = 0 \text{ V}$		_	1.2	V











VDS = -10 V

-30

-100

Pulse test

-10

ŝ

Forward transfer admittance | Y<sub>fs</sub>|

0.3 -0.1

-0.3

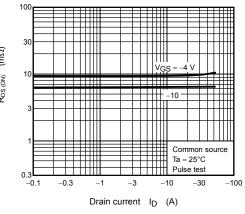
-1

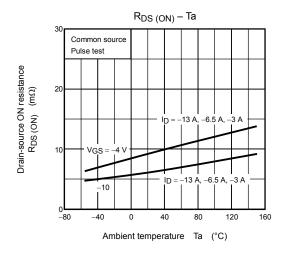
-3

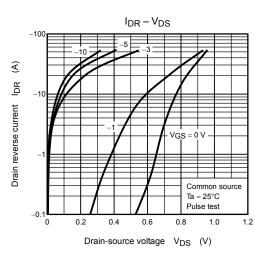
Drain current  $I_D$  (A)

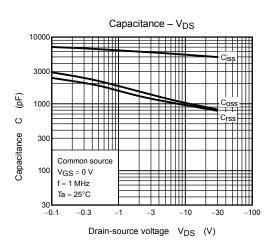


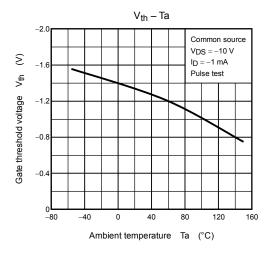
 $R_{DS(ON)} - I_D$ 

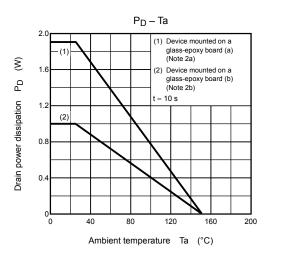


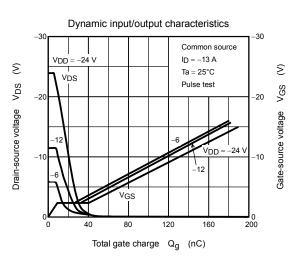


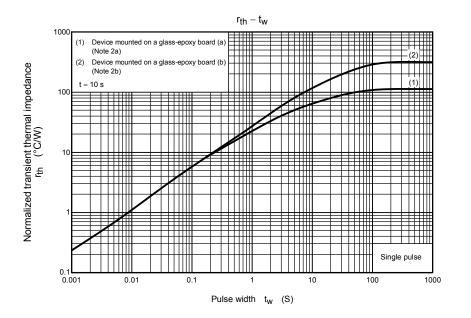




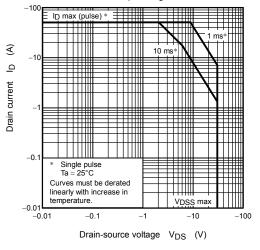








Safe operating area



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